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## German 2015 DGKK Prize awarded to Prof. Dr. Andreas Erb

Ithaca, NY -- (May 14, 2015) -- Multiwire Laboratories, Ltd. (MWL), the leading supplier of equipment for realtime x-ray orientation of single crystals by the Laue back-reflection method, congratulates Prof. Dr. Andreas Erb on being awarded the German 2015 DGKK prize in crystal growth at an event held during the Annual Conference of the Deutsche Gesellschaft für Kristallwachtum und Kristallzüchtung (DGKK) that took place in Frankfurt, Germany from March 04 to 06, 2015.

The prize was awarded for "Outstanding scientific achievements in the field of successful growth of single crystals, especially of complex oxide compounds of highest perfection, from which he and other research groups have obtained new fundamental insights."



Presentation of the 2015 DGKK Prize to Prof. Dr. Andreas Erb by Dr.-Ing. Jochen Friedrich (left, Chairman of DGKK, Fraunhofer Institute for Integrated Systems and Device Technology IISB) and Dr. Wolfgang Löser (right, IFW Dresden). [excerpted from posting at http://www.wmi.badw.de/news/2015/2015\_03\_04.html]

In his primary occupation, Prof. Dr. Andreas Erb is academic director at the Walther-Meissner-Institute for low temperature physics of the Bavarian Academy for Science and Humanities and at the same time scientific director of the Crystal laboratory of the Faculty of Physics at the Technical University of Munich. In December 2012 he was also appointed honorary professor for Experimental Physics at the University of Leipzig (Germany).

On the Multiwire Laboratories side, he handles European sales, installation and training of the real-time x-ray equipment for Multiwire Laboratories of Ithaca, NY where he can be contacted through <a href="http://www.lauecamera.com/">http://www.lauecamera.com/</a> or through email at andreas.erb@lauecamera.com.

## ABOUT MULTIWIRE LABORATORIES, LTD.

Multiwire Laboratories Ltd. develops and manufactures products for rapid x-ray orientation of single crystals by the Laue back-reflection method. Industrial and academic laboratories utilize the real-time detector, motorized orientation stages, and computer analysis of back-reflection images to characterize or determine the orientation of the lattice planes in a variety of crystal materials such as silicon, gallium arsenide, sapphire, geological minerals, high-temperature superconductors, turbine blades, etc. For more information on MWL, visit <a href="www.multiwire.com">www.multiwire.com</a> or contact <a href="mailto:salesinfo@multiwire.com">salesinfo@multiwire.com</a>.

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